

August 2014

FCP16N60 / FCPF16N60 N-Channel SuperFET[®] MOSFET 600 V, 16 A, 260 m Ω

Features

- 650V @ T_J = 150°C
- Typ. $R_{DS(on)}$ = 220 $m\Omega$
- Ultra Low Gate Charge (Typ. $Q_g = 55 \text{ nC}$)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 110 pF)
- 100% Avalanche Tested

Applications

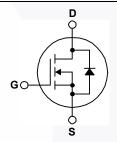
- Solar Inverter
- AC-DC Power Supply

Description

SuperFET® MOSFET is Fairchild Semiconductor's first generation of high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low onresistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications.







Absolute Maximum Ratings

Symbol		Parameter		FCP16N60	FCPF16N60	Unit
V _{DSS}	Drain-Source Voltage		600		V	
I _D	Drain Current	- Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		16 10.1	16* 10.1*	A A
I _{DM}	Drain Current	- Pulsed	(Note 1)	48	48*	Α
V _{GSS}	Gate-Source Volta	ge		±	30	V
E _{AS}	Single Pulsed Avalanche Energy (N		(Note 2)	450		mJ
I _{AR}	Avalanche Current		(Note 1)	16		Α
E _{AR}	Repetitive Avalance	he Energy	(Note 1)	2	0.8	mJ
dv/dt	Peak Diode Recov	ery dv/dt	(Note 3)	4	4.5	
P_{D}	Power Dissipation	(T _C = 25°C) - Derate Above 25°C		167 1.33	37.9 0.3	W W/°C
T _{J,} T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C	
T _L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300		°C	

^{*}Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FCP16N60	FCPF16N60	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.75	3.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCP16N60	FCP16N60	TO-220	Tube	N/A	N/A	50 units
FCPF16N60	FCPF16N60	TO-220F	Tube	N/A	N/A	50 units

Electrical Characteristics T_C = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
D\/	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 25^{\circ} C$	600	-	-	V
BV _{DSS}	Drain to Source Breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 150^{\circ} C$	-	650	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
BV _{DS}	Drain-Source Avalanche Breakdown Voltage	V _{GS} = 0 V, I _D = 16 A	_	700	-	V
1	Zero Gate Voltage Drain Current	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	1	
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	10	μΑ
I _{GSS}	Gate to Body Leakage Current	V _{GS} = ±30 V, V _{DS} = 0 V	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	-	0.55	0.26	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 8 A	-	11.5	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05.V.V 0.V	-	1730	2250	pF
C _{oss}	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	-	960	1150	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	-	85	-	pF
C _{oss}	Output Capacitance	V _{DS} = 480 V, V _{GS} = 0 V, f = 1 MHz	-	45	60	pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V	-	110	-	pF
Qg	Total Gate Charge at 10V	V _{DS} = 480 V, I _D = 16 A,	-	55	70	nC
Q _{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	10.5	13	nC
Q_{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	28	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-/	1.7	-	Ω

Switching Characteristics

_						
t _{d(on)}	Turn-On Delay Time		/ · -	42	85	ns
t _r	Turn-On Rise Time	V _{DD} = 300 V, I _D = 16 A,	-	130	270	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_G = 25 Ω	-	165	340	ns
t _f	Turn-Off Fall Time	(Note 4	-	90	190	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current		-	_	16	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			_	48	Α
V_{SD}	Drain to Source Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_{SD} = 16 \text{ A}$		-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 16 A,	-	435	\ -	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	7.0	-	μС

Notes

- ${\it 1:} \ \ {\it Repetitive\ rating: pulse-width\ limited\ by\ maximum\ junction\ temperature.}$
- 2: I_{AS} = 8 A, V_{DD} = 50 V, R_G = 25 Ω , starting T_J = 25°C.
- 3: $I_{SD} \le 16$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, starting $T_J = 25^{\circ}C$.
- 4: Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

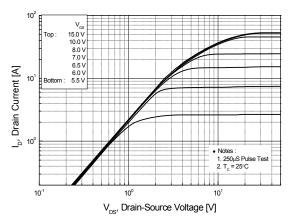


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

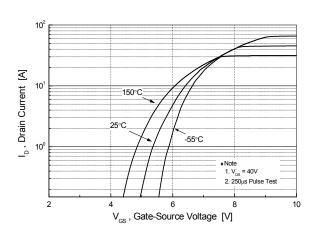
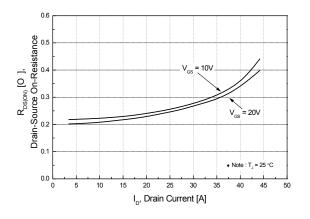


Figure 2. Transfer Characteristics

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue



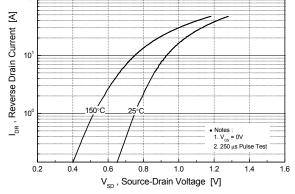


Figure 5. Capacitance Characteristics

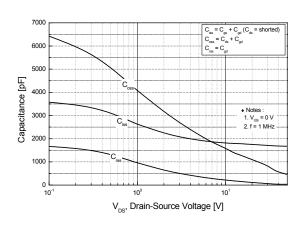
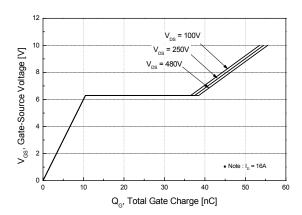


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

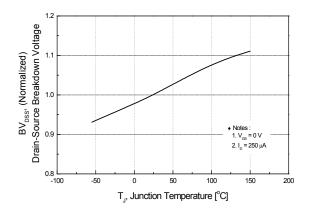


Figure 8. On-Resistance Variation vs. Temperature

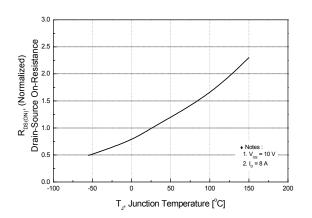


Figure 9-1. Maximum Safe Operating Area for FCP16N60

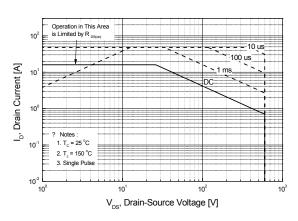


Figure 9-2. Maximum Safe Operating Area for FCPF16N60

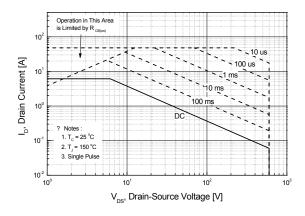
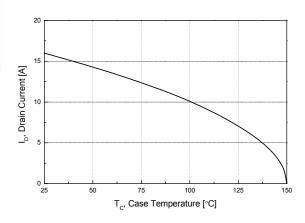


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve for FCP16N60

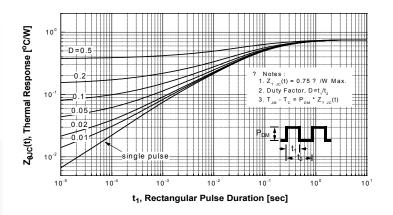
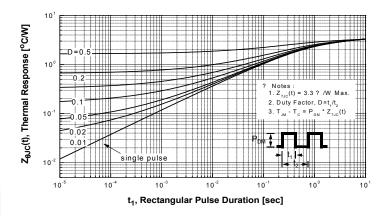


Figure 11-2. Transient Thermal Response Curve for FCPF16N60



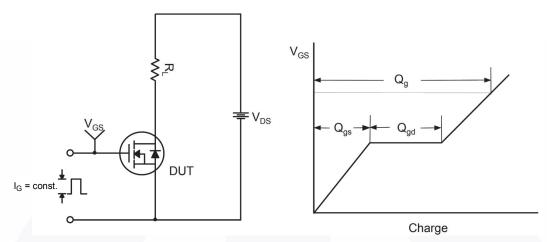


Figure 12. Gate Charge Test Circuit & Waveform

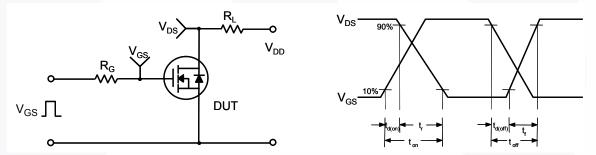


Figure 13. Resistive Switching Test Circuit & Waveforms

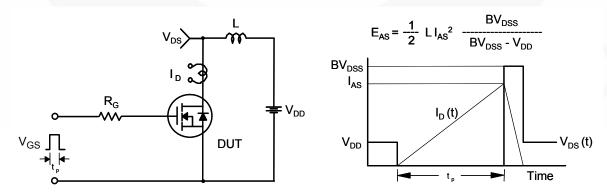


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

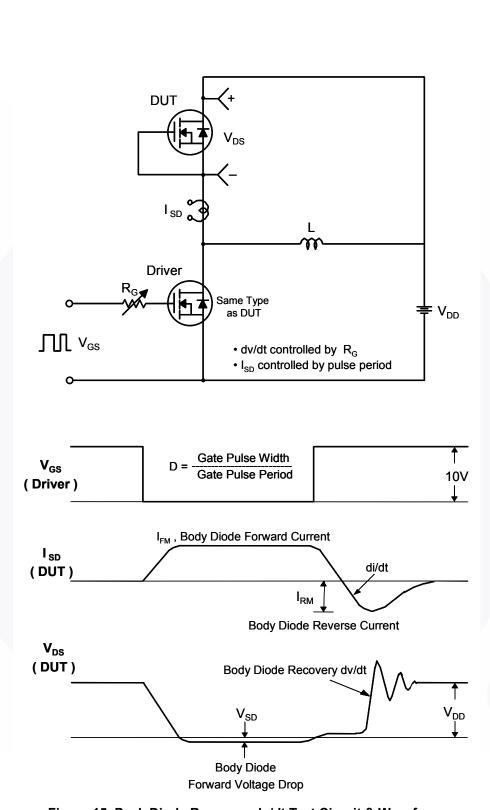
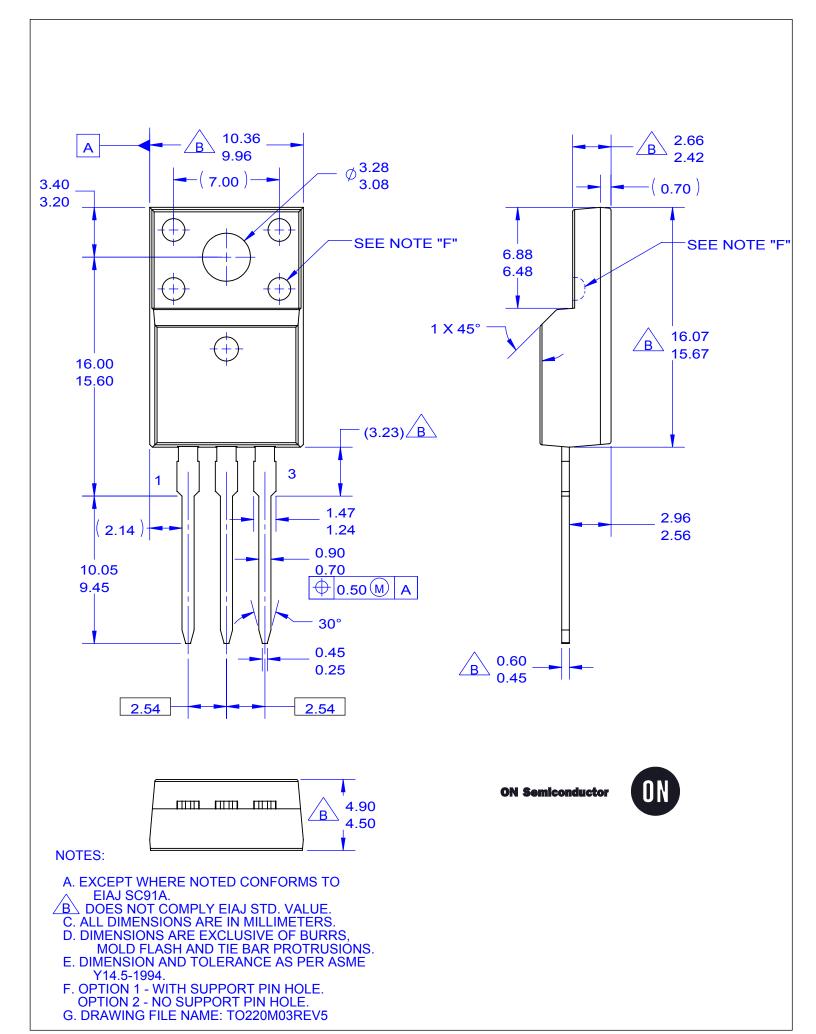


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms





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